

WORKSHOP COORDINATOR

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(Streumethoden)

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LOCAL ORGANIZATION COMMITTEE

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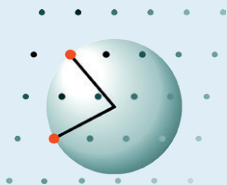
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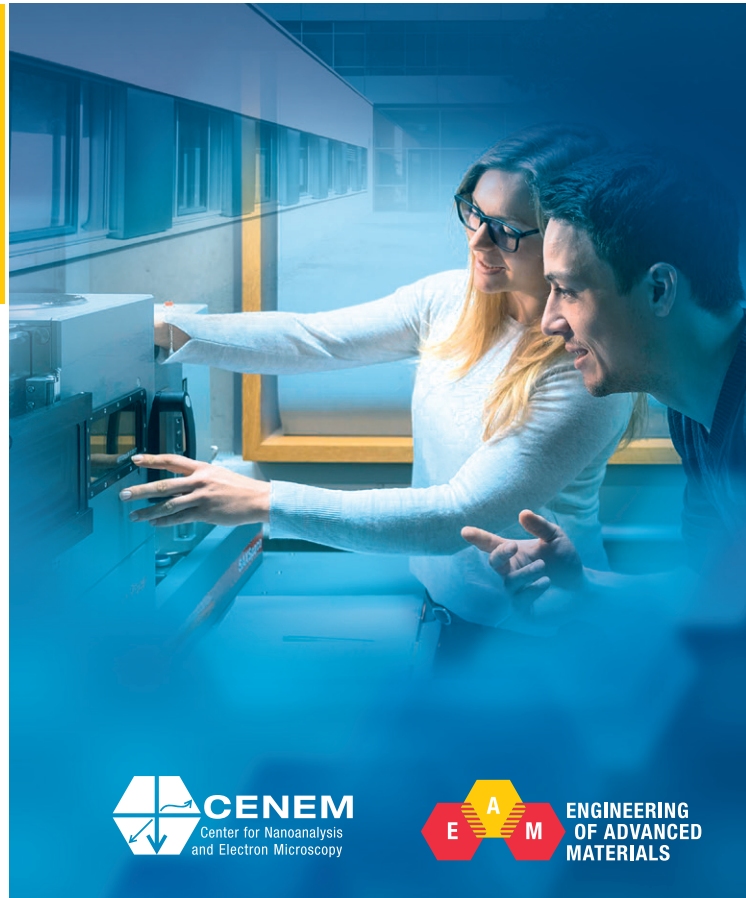


FRIEDRICH-ALEXANDER
UNIVERSITÄT
ERLANGEN-NÜRNBERG

4th CENEM Summer School for X-ray Scattering 2018

16 – 19 July 2018

Institute for Crystallography and Structural Physics
Friedrich-Alexander-Universität Erlangen-Nürnberg
Staudtstraße 3, 91058 Erlangen



Program

MONDAY 16TH JULY 2018

**Introduction into the different methods
and contents of the summer school**

9⁰⁰ Welcome Prof. Tobias Unruh

9¹⁰ Powder diffraction (XRD) Prof. Rainer Hock

10¹⁰ Small angle X-ray scattering (SAXS)
Prof. Tobias Unruh

10³⁰ Coffee break

11⁰⁰ Reflectometry (XRR) Klaus Götz, M. Sc.

**11³⁰ Grazing incidence scattering
(GISAXS, GIWAXS)** Marvin Berlinghof, M. Sc.

12⁰⁰ Coffee break

12¹⁵ Neutron scattering at large scale facilities
Dr. Sebastian Busch (FRM II, München)

13⁰⁰ X-ray safety briefing Dr. Matthias Weisser

13³⁰ Lunch

14³⁰ Hands-on training I

TUESDAY 17TH JULY 2018

**Powder diffraction and pair
distribution function**

9⁰⁰ Data analysis of powder diffractograms
Prof. Rainer Hock

10³⁰ Coffee break

11⁰⁰ Full pattern profile fitting Prof. Rainer Hock

12⁰⁰ Coffee break

12¹⁵ Pair distribution function analysis
Prof. Reinhard Neder

13⁰⁰ Lunch

14⁰⁰ Hands-on training II

WEDNESDAY 18TH JULY 2018

Small angle scattering

**9⁰⁰ Introduction into small angle scattering (SAS)
Advanced applications of SAS**
Prof. Tobias Unruh

10³⁰ Coffee break

**11⁰⁰ SAS instrumentation and data analysis
with discussion** Prof. Tobias Unruh

12³⁰ Lunch

13³⁰ Hands-on training III

THURSDAY 19TH JULY 2018

**Thin film analysis: reflectometry
and grazing incidence scattering**

**9⁰⁰ X-ray reflectometry for studies
of layered systems** Klaus Götz, M. Sc.

10³⁰ Coffee break

11⁰⁰ GISAXS/GIWAXS for studying thin films
Marvin Berlinghof, M. Sc. · Dr. Wolfgang Gruber

12³⁰ Lunch

13³⁰ Hands-on training IV

17³⁰ Barbeque